

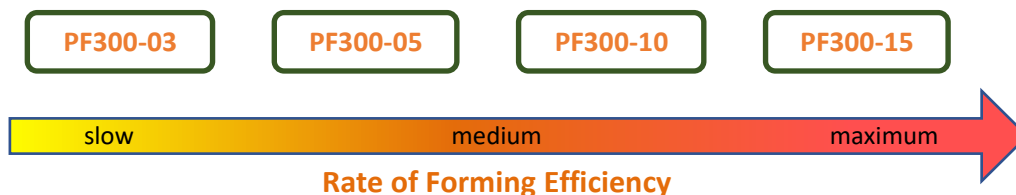


## GENERAL

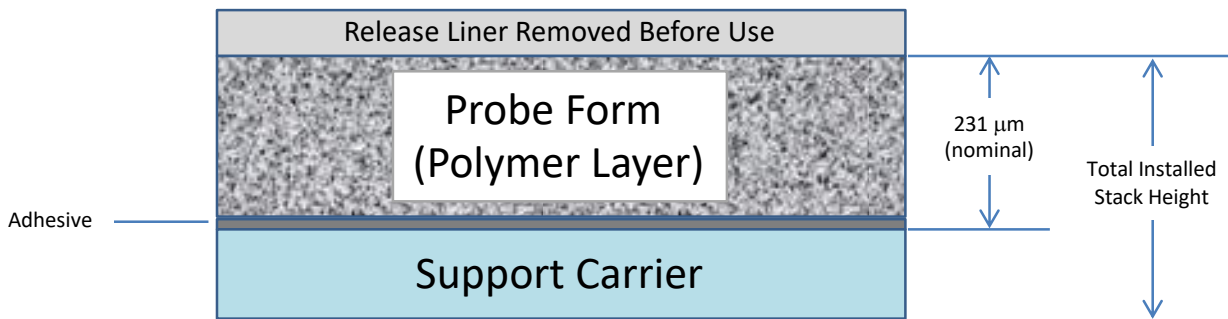
Probe Form® and Probe Form®-A were developed to provide cost effective methods of uniformly “forming” and “reforming” probe tip geometries. Probe Form® and Probe Form®-A use highly crosslinked, non-corrosive silicone-based polymers specifically designed to remove probe material.

The primary forming action with Probe Form® is created by insertions in the Z direction only. Minimal lateral forces are applied to the probes during forming. Forces exerted on the probe with Probe Form® will be significantly less than the forces as during normal testing operations.

During forming, the probe tips should be inspected and measured frequently to determine the material removal and rate of shaping. It is possible to attain tip changes in less than 1000 touchdowns; however, the overall shaping rate will depend on the tip shape, tip size, and probe material. The total number of insertions will vary according to customer requirements. To achieve maximum forming efficiency, offset each touchdown location approximately 2X the probe diameter in the XY directions.



## CROSS SECTION



	Cleaning Material Configuration			
	Sheet	200mm Wafer	300mm Wafer	Custom Install
<b>Polymer Layer Thickness</b>	231 μm (nominal)	231 μm (nominal)	231 μm (nominal)	231 μm (nominal)
<b>Support Carrier</b>	143 μm (PET nominal)	725 ± 20μm (SEMI Standard)	775 ± 20μm (SEMI Standard)	Contact ITS
<b>Total Installed Stack Height</b>	374 ± 20μm	956 ± 30μm	1006 ± 30 μm	Contact ITS

PROBE FORM®

PCC PD-PF001

